



FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. : <b>BA-22878</b>	SERIAL NO. <b>10/828,435</b>
LIST OF REFERENCES CITED BY APPLICANT  (Use several sheets if necessary)		APPLICANT: <b>Kung-Hwa WEI ET AL</b>		
		FILING DATE: <b>4/20/2004</b>	GROUP: <b>(712)</b>	

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
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	AH						
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	AJ						
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>Gyp</i>	AQ	Eashoo, M.; Buckley, L.J.; StClair, A.K. <i>J. Polym. Sci.</i> Part B: <i>Polym. Phys.</i> , 1997, 35, 173					
	AR	Hedrick, J.L.; Miller, R.D.; Hawker, C.J.; Carter, K.R.; Volksen, W.; Yoon, D.Y.; Trollsas, M. <i>Adv. Mater.</i> , 1998, 10, 1049					
	AS	Carter, K.R.; DiPietro, R.A.; Sanchez, M.I.; Russell, T.P.; Lakshmanan, P.; McGrath, J.E. <i>Chem. Mater.</i> 1997, 9, 105					
	AT	Hedrick, J.L.; Carter, K.R.; Richter, R.; Miller, R.D.; Russell, T.P.; Flores, V. <i>Chem Mater.</i> 1998, 10(1), 39					
<i>V</i>	AU	Carter, K.R.; DiPietro, R.A.; Sanchez, M.I.; Swanson, S.A. <i>Chem. Mater.</i> , 2001, 13, 213					

EXAMINER	<i>L.H. Peleg</i>	DATE CONSIDERED	<i>12/15/05</i>
'EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.'			

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		FILING DATE: <b>4/20/2004</b>	GROUP: <b>1712</b>		

*4/14/2004*

## U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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	AI					
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	AK					

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✓	AT	M.T. Bogert and R.R. Renshaw, J.Am. Chem. Sci., 1908, 30, 1135
✓	AU	T.L. Porter et al., J. Polymer Sci., Part B: Polym. Phys., 1998, 36, 673
✓	AV	A. Okada et al., Mater. Sci. Eng., 1995, 3, 109

EXAMINER

*Kung-Hwa Wei*

DATE CONSIDERED

*12/16/05*

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